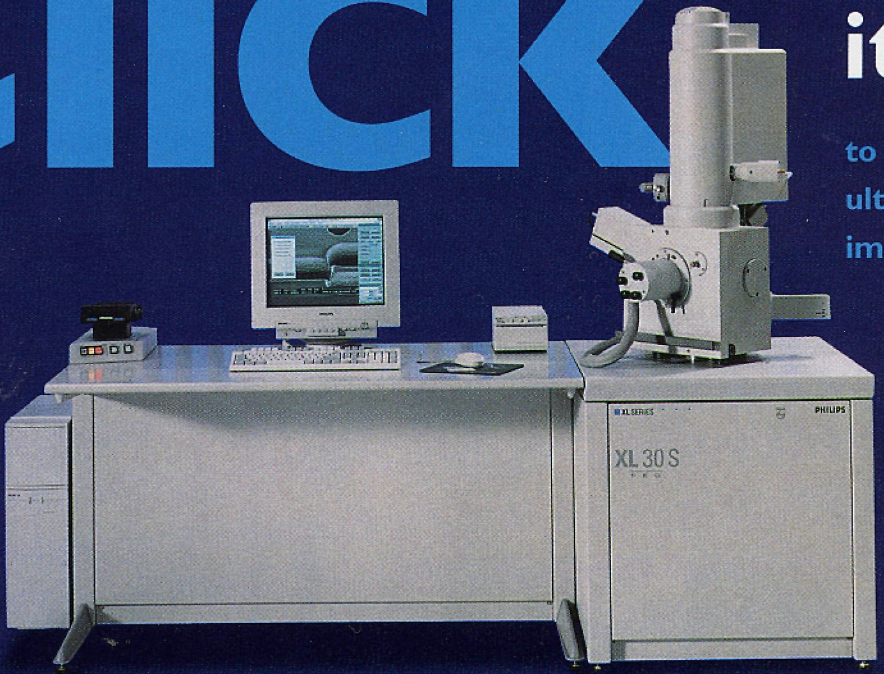
Click that's all it takes

to go from high to ultra-high resolution imaging



Navigate your sample with low-magnification TV-rate imaging. Determine where to zoom in. Then click the mouse button, and the XL30 S FEG scanning electron microscope with its unique Hexalens automatically switches to ultra-high resolution mode. Your sample stays in view, and you get an amazingly detailed image of the uncoated specimen.

High magnification, low kV

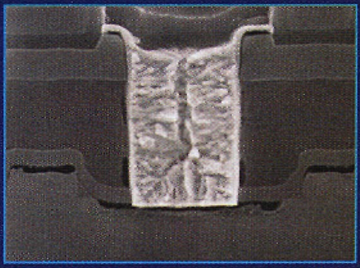
The XL30 is the SEM for high-magnification, low-kV imaging in materials research, life sciences and semiconductors. Low kV means there's no need for coatings that could damage or hide the very features you are interested in.

Dual-mode Hexalens

With its six-coil construction, the Hexalens column provides dual-mode operation. The standard 'field-free' mode, with its enhanced depth of focus and topography, is ideal for initial navigation. Switch to the ultra-high resolution 'immersion' mode and you get an altogether sharper, more detailed and brighter image, even for highly tilted samples at low kV.

The XL30 detects both secondary electrons (SE) and backscattered electrons (BSE) below 1kV, and at TV-rate. It allows you to change between SE and BSE detection to examine specific features of a sample.

Contact us for more about the XL30 S FEG's highlights.



Semiconductor cross-section of W-plug at 50.000x

HEXALENS *The unique Hexalens on the XL30 S FEG allows you to switch from standard high-resolution mode to an ultra-high resolution mode across the instrument's full kV range, even below 1 kV! Materials like plastics, polymers and ceramics need no conductive metal coating.*

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